SN74AHC573-Q1 Automotive Octal Transparent D-Type Latch With 3-State Outputs

1 Features

- Qualified for automotive applications
- Operating range 2V to 5.5V V_{CC}
- 3-state outputs directly drive bus lines

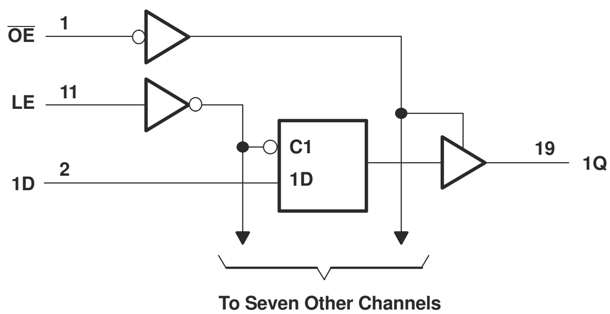
2 Description

The SN74AHC573 is an octal transparent D-type latch designed for 2V to 5.5V V_{CC} operation.

Package Information

PART NUMBER	PACKAGE[(1)]	PACKAGE SIZE[(2)]	BODY SIZE[(3)]
SN74AHC573-Q1	PW (TSSOP, 20)	6.50mm × 6.4mm	6.50mm × 4.40mm

(1) For more information, see Mechanical, Packaging, and Orderable Information.
(2) The package size (length × width) is a nominal value and includes pins, where applicable.
(3) The body size (length × width) is a nominal value and does not include pins.



Logic Diagram (Positive Logic)

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3 Pin Configuration and Functions

PW PACKAGE
(TOP VIEW)

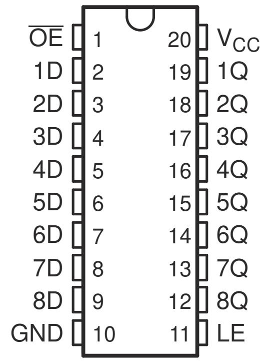


Figure 3-1. PW Package, 20-Pin TSSOP (Top View)

PIN		I/O[1]	DESCRIPTION
NO.	NAME		
1	$\overline{OE}$	I	Output Enable
2	1D	I	1D Input
3	2D	I	2D Input
4	3D	I	3D Input
5	4D	I	4D Input
6	5D	I	5D Input
7	6D	I	6D Input
8	7D	I	7D Input
9	8D	I	8D Input
10	GND	—	Ground
11	LE	I	Latch Enable
12	8Q	O	8Q Output
13	7Q	O	7Q Output
14	6Q	O	6Q Output
15	5Q	O	5Q Output
16	4Q	O	4Q Output
17	3Q	O	3Q Output
18	2Q	O	2Q Output
19	1Q	O	1Q Output
20	V_{CC}	—	Power Pin

1. I = input, O = output, P = power, FB = feedback, GND = ground, N/A = not applicable

4 Specifications

4.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC}	Supply voltage range		–0.5	7	V
V_I	Input voltage range(1)		–0.5	7	V
V_O	Output voltage range(1)		–0.5	V_{CC} + 0.5	V
I_{IK}	Input clamp current	$V_I < 0$		–20	mA
I_{OK}	Output clamp current	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
I_O	Continuous output current	V_O = 0 to V_{CC}		±25	mA
	Continuous current through V_{CC} or GND			±75	mA
T_{stg}	Storage temperature range		–65	150	°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

4.2 ESD Ratings

			Value	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per AEC Q100-002(1)	±1000	V
		Charged device model (CDM), per AEC Q100-011	±1000	

(1) AEC Q100-002 indicates that HBM stressing must be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

4.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

			–40°C to 125°C		–40°C to 85°C		UNIT
			MIN	MAX	MIN	MAX	
V_{CC}	Supply voltage		2	5.5	2	5.5	V
V_{IH}	High-level input voltage	V_{CC} = 2V	1.5		1.5		V
		V_{CC} = 3V	2.1		2.1		
		V_{CC} = 5.5V	3.85		3.85		
V_{IL}	Low-level input voltage	V_{CC} = 2V		0.5		0.5	V
		V_{CC} = 3V		0.9		0.9	
		V_{CC} = 5.5V		1.65		1.65	
V_I	Input voltage		0	5.5	0	5.5	V
V_O	Output voltage		0	V_{CC}	0	V_{CC}	V
I_{OH}	High-level output current	V_{CC} = 2V		–50		–50	µA
		V_{CC} = 3.3V ± 0.3V		–4		–4	mA
		V_{CC} = 5V ± 0.5V		–8		–8	
I_{OL}	Low-level output current	V_{CC} = 2V		50		50	µA
		V_{CC} = 3.3V ± 0.3V		4		4	mA
		V_{CC} = 5V ± 0.5V		8		8	
Δt/Δv	Input transition rise or fall rate	V_{CC} = 3.3V ± 0.3V		100		100	ns/V
		V_{CC} = 5V ± 0.5V		20		20	
T_A	Operating free-air temperature		–40	125	–40	85	°C

(1) All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

4.4 Thermal Information

THERMAL METRIC[1]		SN74AHC573-Q1 PW (TSSOP) 20 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	83	°C/W

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report (SPRA953).

4.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	T_A = 25°C			–40°C to 125°C		–40°C to 85°C		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V_{OH}	I_{OH} = –50µA	2V	1.9	2		1.9		1.9		V
		3V	2.9	3		2.9		2.9		
		4.5V	4.4	4.5		4.4		4.4		
	I_{OH} = –4mA	3V	2.58			2.48		2.48		
	I_{OH} = –8mA	4.5V	3.94			3.8		3.8		
V_{OL}	I_{OL} = 50µA	2V			0.1		0.1		0.1	V
		3V			0.1		0.1		0.1	
		4.5V			0.1		0.1		0.1	
	I_{OL} = 4mA	3V			0.36		0.5		0.44	
	I_{OL} = 8mA	4.5V			0.36		0.5		0.44	
I_I	V_I = 5.5V or GND	0V to 5.5V			±0.1		±1		±1	µA
I_{OZ}	V_I = V_{IL} or V_{IH}, V_O = V_{CC} or GND	5.5V			±0.25		±2.5		±2.5	µA
I_{CC}	V_I = V_{CC} or GND, I_O = 0	5.5V			4		40		40	µA
C_i	V_I = V_{CC} or GND	5V		2.5	10				10	pF
C_o	V_O = V_{CC} or GND	5V		3.5						pF

4.6 Timing Requirements, V_{CC} = 3.3V ± 0.3V

over recommended operating free-air temperature range, V_{CC} = 3.3V ± 0.3V (unless otherwise noted) (see Load Circuits and Voltage Waveforms)

		T_A = 25°C		–40°C to 125°C		–40°C to 85°C		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
t_w	Pulse duration, LE high	5		5		5		ns
t_{su}	Setup time, data before LE↓	3.5		3.5		3.5		ns
t_h	Hold time, data after LE↓	1.5		1.5		1.5		ns

4.7 Timing Requirements, V_{CC} = 5V ± 0.5V

over recommended operating free-air temperature range, V_{CC} = 5V ± 0.5V (unless otherwise noted) (see Load Circuits and Voltage Waveforms)

		T_A = 25°C		–40°C to 125°C		–40°C to 85°C		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
t_w	Pulse duration, LE high	5		5		5		ns
t_{su}	Setup time, data before LE↓	3.5		3.5		3.5		ns
t_h	Hold time, data after LE↓	1.5		1.5		1.5		ns

4.8 Switching Characteristics, V_{CC} = 3.3V ± 0.3V

over recommended operating free-air temperature range, V_{CC} = 3.3V ± 0.3V (unless otherwise noted) (see Load Circuits and Voltage Waveforms)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	T_A = 25°C			–40°C to 125°C		–40°C to 85°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	D	Q	C_L = 50pF		9.5	14.5	1	16.5	1	16.5	ns
t_{PHL}					9.5	14.5	1	16.5	1	16.5	
t_{PLH}	LE	Q	C_L = 50pF		10.1	15.4	1	17.5	1	17.5	ns
t_{PHL}					10.1	15.4	1	17.5	1	17.5	
t_{PZH}	$\overline{OE}$	Q	C_L = 50pF		9.8	15	1	17	1	17	ns
t_{PZL}					9.8	15	1	17	1	17	
t_{PHZ}	$\overline{OE}$	Q	C_L = 50pF		10.7	14.5	1	16.5	1	16.5	ns
t_{PLZ}					10.7	14.5	1	16.5	1	16.5	

4.9 Switching Characteristics, V_{CC} = 5V ± 0.5V

over recommended operating free-air temperature range, V_{CC} = 5V ± 0.5V (unless otherwise noted) (see Load Circuits and Voltage Waveforms)

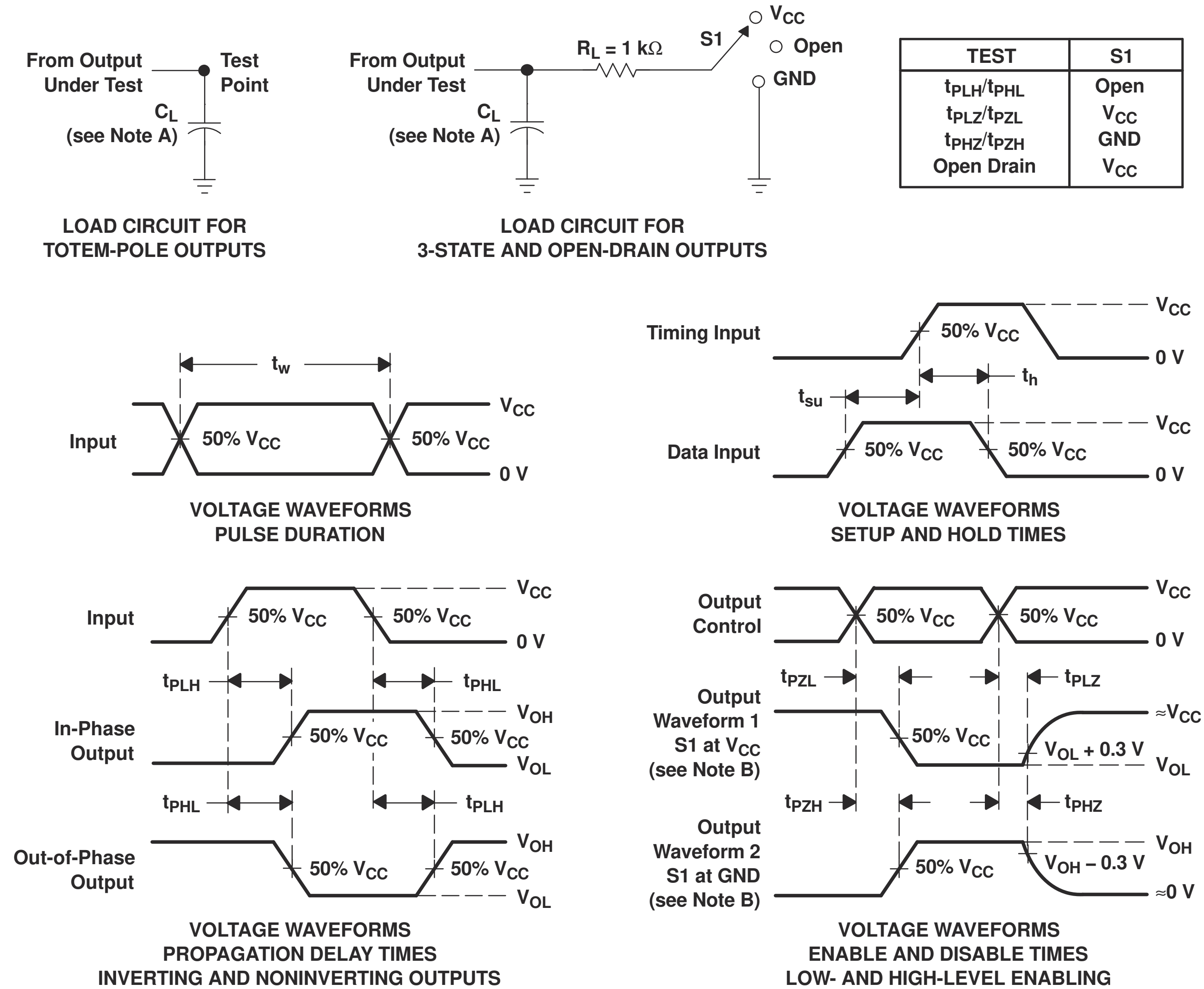
PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	T_A = 25°C			–40°C to 125°C		–40°C to 85°C		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	D	Q	C_L = 50pF		6	8.8	1	10	1	10	ns
t_{PHL}					6	8.8	1	10	1	10	
t_{PLH}	LE	Q	C_L = 50pF		6.5	9.7	1	11	1	11	ns
t_{PHL}					6.5	9.7	1	11	1	11	
t_{PZH}	$\overline{OE}$	Q	C_L = 50pF		6.7	9.7	1	11	1	11	ns
t_{PZL}					6.7	9.7	1	11	1	11	
t_{PHZ}	$\overline{OE}$	Q	C_L = 50pF		6.7	9.7	1	11	1	11	ns
t_{PLZ}					6.7	9.7	1	11	1	11	

4.10 Operating Characteristics

V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS		TYP	UNIT
C_{pd}	Power dissipation capacitance	No load,	f = 1 MHz	16	pF

5 Parameter Measurement Information



TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	V_{CC}
t_{PHZ}/t_{PZH}	GND
Open Drain	V_{CC}

NOTES:
A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r ≤ 3 ns, t_f ≤ 3 ns.
D. The outputs are measured one at a time, with one input transition per measurement.
E. All parameters and waveforms are not applicable to all devices.

Figure 5-1. Load Circuits and Voltage Waveforms

6 Detailed Description

6.1 Overview

When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is low, the Q outputs are latched at the logic levels of the D inputs.

A buffered output-enable ($\overline{OE}$) input can be used to place the eight outputs in either a normal logic state (high or low) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

$\overline{OE}$ does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

6.2 Functional Block Diagram

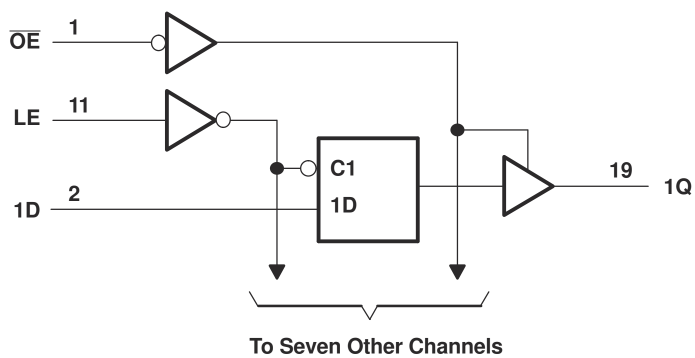


Figure 6-1. Logic Diagram (Positive Logic)

6.3 Device Functional Modes

Table 6-1. Function Table (Each Latch)

INPUTS			OUTPUT Q
$\overline{OE}$	LE	D	
L	H	H	H
L	H	L	L
L	L	X	Q_0
H	X	X	Z

7 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

7.1 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1μF capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The 0.1μF and 1μF capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

7.2 Layout

7.2.1 Layout Guidelines

- Bypass capacitor placement
  - Place near the positive supply terminal of the device
  - Provide an electrically short ground return path
  - Use wide traces to minimize impedance
  - Keep the device, capacitors, and traces on the same side of the board whenever possible
- Signal trace geometry
  - 8mil to 12mil trace width
  - Lengths less than 12cm to minimize transmission line effects
  - Avoid 90° corners for signal traces
  - Use an unbroken ground plane below signal traces
  - Flood fill areas around signal traces with ground
  - For traces longer than 12cm
    - Use impedance controlled traces
    - Source-terminate using a series damping resistor near the output
    - Avoid branches; buffer signals that must branch separately

7.2.2 Layout Example

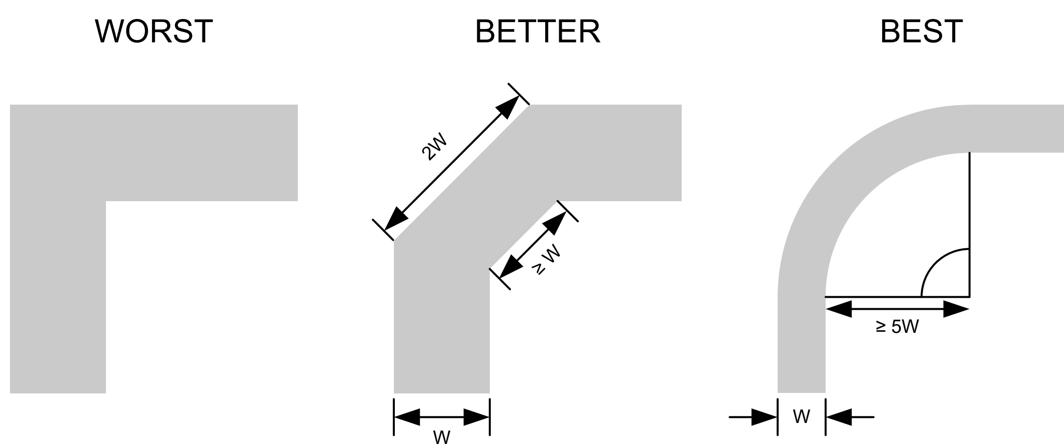


Figure 7-1. Example Trace Corners for Improved Signal Integrity

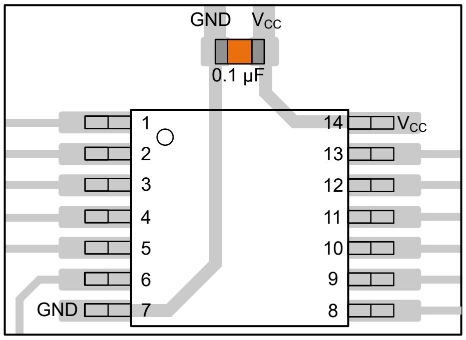


Figure 7-2. Example Bypass Capacitor Placement for TSSOP and Similar Packages

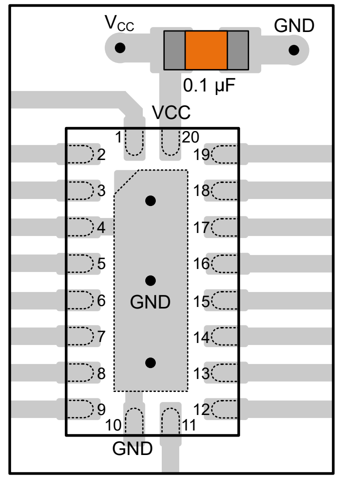


Figure 7-3. Example Bypass Capacitor Placement for WQFN and Similar Packages

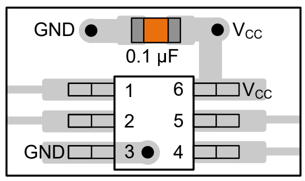


Figure 7-4. Example Bypass Capacitor Placement for SOT, SC70 and Similar Packages

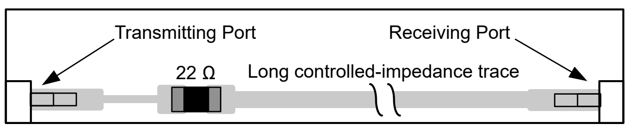


Figure 7-5. Example Damping Resistor Placement for Improved Signal Integrity

8 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

8.1 Documentation Support

8.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, *CMOS Power Consumption and C_{pd} Calculation* application report
- Texas Instruments, *Designing With Logic* application report
- Texas Instruments, *Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices* application report

8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

8.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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8.4 Trademarks

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8.5 Electrostatic Discharge Caution

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

8.6 Glossary

TI Glossary   This glossary lists and explains terms, acronyms, and definitions.

9 Revision History

Changes from Revision A (April 2008) to Revision B (January 2025) **Page**

- Added *Package Information* table, *Pin Functions* table, *ESD Ratings* table, *Thermal Information* table, *Device Functional Modes,* Application and Implementation section, *Device and Documentation Support* section, and *Mechanical, Packaging, and Orderable Information* section 1

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN74AHC573QPWRG4Q1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HA573Q	Samples
SN74AHC573QPWRQ1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HA573Q	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

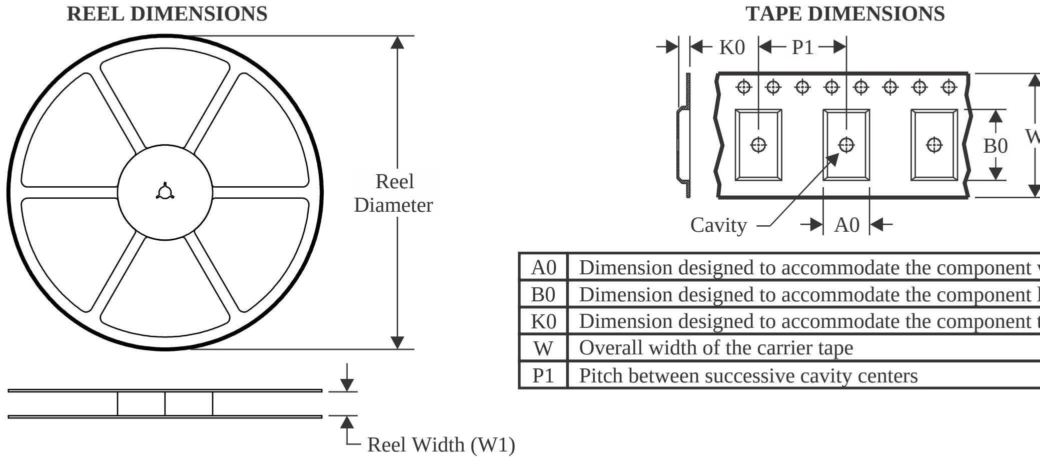
OTHER QUALIFIED VERSIONS OF SN74AHC573-Q1 :

- Catalog : SN74AHC573
- Military : SN54AHC573

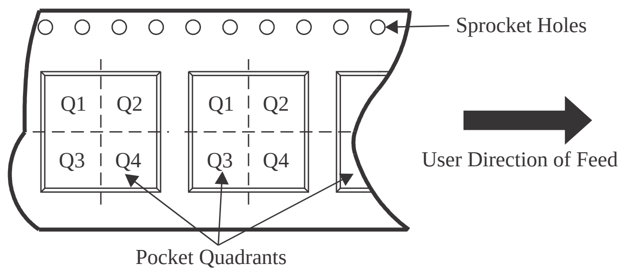
NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION



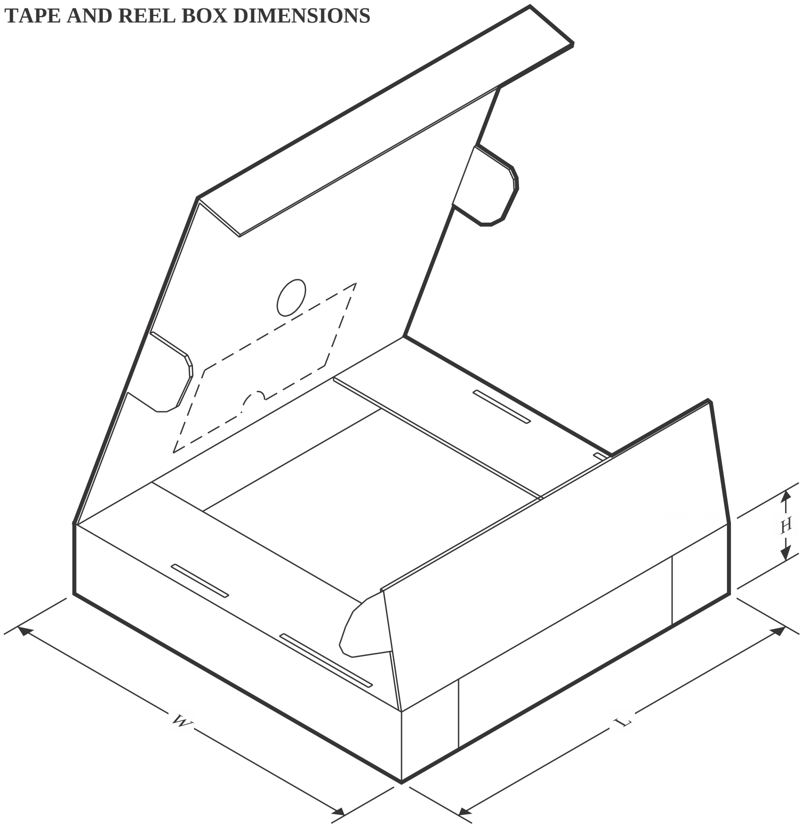
A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers



*All dimensions are nominal

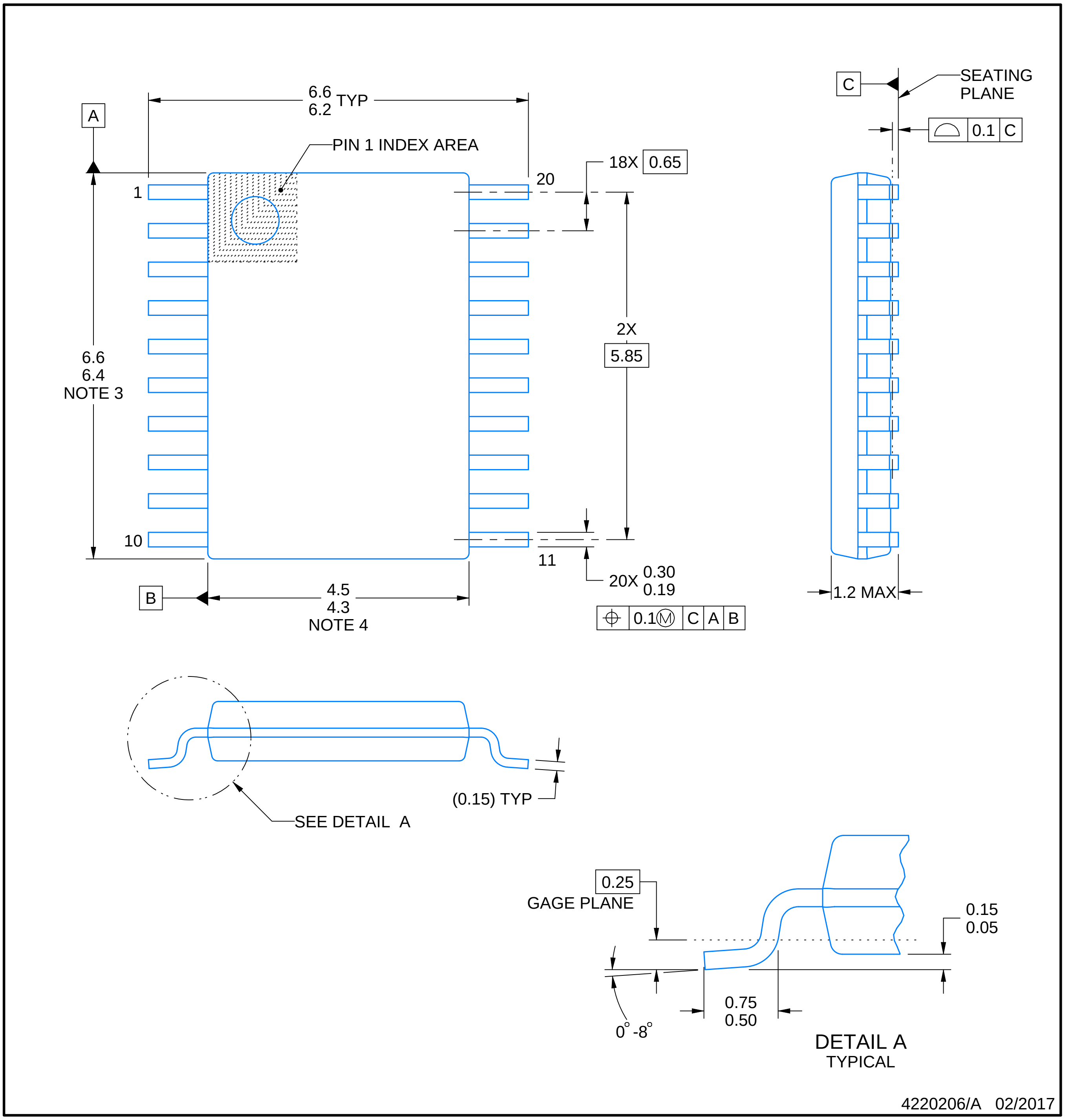
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHC573QPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74AHC573QPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS



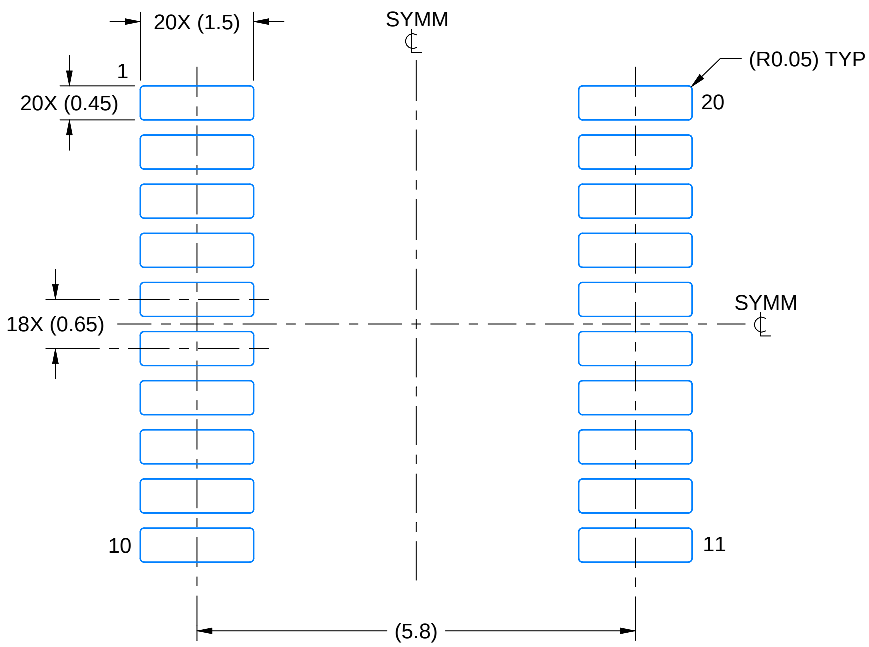
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHC573QPWRG4Q1	TSSOP	PW	20	2000	356.0	356.0	35.0
SN74AHC573QPWRQ1	TSSOP	PW	20	2000	356.0	356.0	35.0

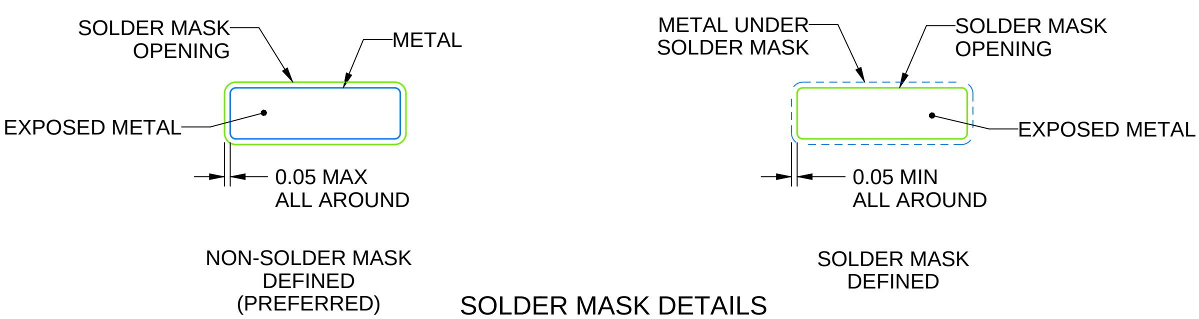


NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X



SOLDER MASK DETAILS

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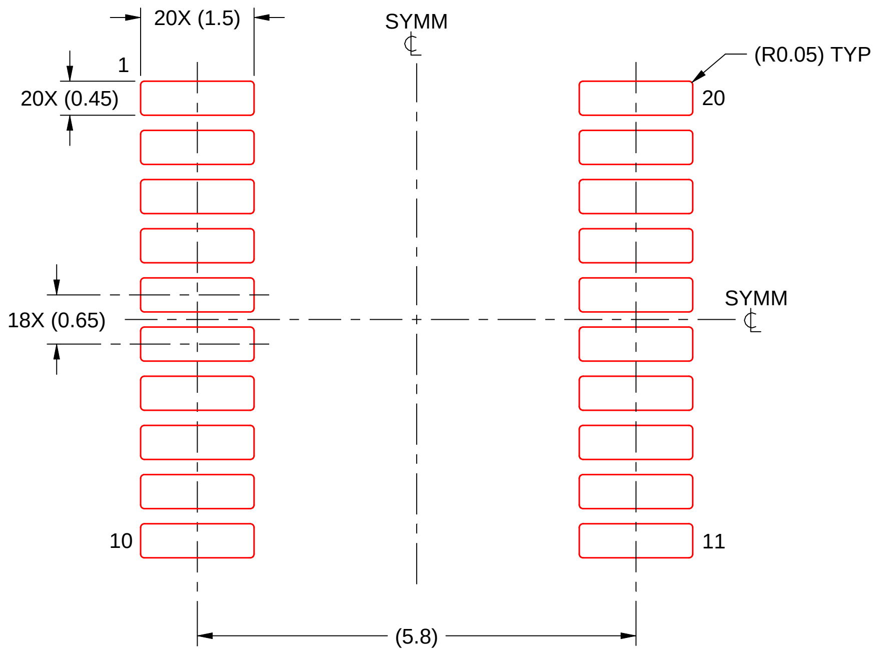
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

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NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.